

Notice of References Cited

Application/Control No.

09/679,969

Applicant(s)/Patent Under
Reexamination
TANAKA, MOTOSHI

Examiner

Pablo N Tran

Art Unit

2685

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,032,053	02-2000	Schroeder et al.	455/553.1
	B	US-5,943,611	08-1999	Molne, Anders Lennart	455/564
	C	US-5,956,632	09-1999	Shon, Jung-Hak	455/404.1
	D	US-6,236,867	05-2001	Todo et al.	455/563
	E	US-6,327,482	12-2001	Miyashita, Toshikazu	455/566
	F	US-6,307,922	10-2001	Scherer, Gordon F.	379/91.02
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 61224645 A (Eng. Ab.)	10-1986	Japan	MURAI et al.	H04M 01/57
	O	JP 09233215 A (Eng. Ab.)	09-1997	Japan	SHIMODA, SHINICHI	H04M 11/00
	P	JP 02032654 A (Eng. Ab.)	02-1990	Japan	TANAKA et al.	H04M 01/26
	Q	JP 10173756 A (Eng. Ab.)	06-1998	Japan	OTONARI et al.	H04M 01/274
	R	JP 09284379 A (Eng. Ab.)	10-1997	Japan	ABE et al.	H04M 01/274
	S	JP 59228454 A (Eng. Ab.)	12-1984	Japan	KITAJIMA et al.	H04M 01/274
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.